

Application/Control No.	Applicant(s)/Patent under Reexamination	
09/670,119	YUMIBA ET AL.	
Examiner	Art Unit	
Shin-Hon Chen	2131	

SEARCHED					
Class	Subclass	Date	Examiner		
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INTERFERENCE SEARCHED					
Class	Subclass	Date	Examiner		
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SEARCH NOTES (INCLUDING SEARCH STRATEGY)				
	DATE	EXMR		
USPAT, PGPUB, JPO, EPO, DERWENT (BRS Search)	7/20/2006	S.C.		